

Meeting Critical Flatness Specifications of Mirror Holders



Field of Application

- VIB Vibration measurement using laser Doppler vibrometry
- LSV Velocity and length measurements using laser surface velocimetry
- TOP Measurement of surface topography using whitelight interferometry
- ST Measurement of spectral material properties using NIR spectrometry

Critically precise mirror holders are used in the Geometry Scan Unit of Polytec's Scanning Vibrometer. These holders are manufactured in an automated machining center installed in Polytec's production machine shop. Stresses induced in the part from the machining can impair the flatness of the mirror mounting surface. Deviations from acceptable flatness tolerances were identified using a TopMap Topography Measurement System and were corrected appropriately in the manufacturing process.

Precision is the Key

To perform correctly, the Geometry Scan Unit of the scanning vibrometer sensor head (image below) must direct the probe laser to the required measurement points using software control. The mirror holders must be manufactured with great precision to hold the optic accurately. Starting with an aluminum rod, the outer surfaces, windows and holes are turned and milled in a single run using a CNC machining center.





Fig. 1: Mirror holder for the PSV geometry scan unit.

The mirror holder is a complex structure (Fig. 1) with narrow portions that can twist and distort during and after manufacturing. The effect of these distortions is to move the mounting surfaces and misalign the mirror. If the flatness of the mounting surface falls below a critical value, the mirror will be out of alignment and will not work properly.

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Flatness Measurements – Tactile or Optical

The mounting surface is very intricate and is made up of relatively narrow, partially recessed ligaments. It was not possible to determine the flatness with a conventional tactile sensor system because only a small portion of the surface was accessible to the scanner tip.



Fig. 2: Measurement setup with TopMap Metro.Lab White-Light Interferometer.

This situation was easily solved with the TopMap Topography Measurement System. The non-contact optical measurement procedure allows the characterization of almost any surface, independently of it specific geometry constraints. The simple-to-use TMS-100 TopMap Metro.Lab was chosen to determine the flatness of the mirror holder quickly and with high precision (Fig. 2).

Results and Conclusions

Following ISO 1101, a comparison was made of the flatness of a good mirror holder (Fig. 3) and a defective mirror holder (Fig. 4). The measurements show that deviations of up to 100% can occur. The good part shows a flatness of about 15 μ m, where as the flatness of the defective part is more than 30 μ m. With the aid of these measurements, it was possible to adapt the manufacturing process to minimize the stress causing the deformations. The manufactured parts now have the required flatness without any further efforts being taken. Thus, when setting up the machining center, an early examination of the



Fig. 3: A good mirror holder shows a flatness measurement (<15 μ m) that is within dimensional tolerances (ISO 1101).

workpieces using the TopMap Metro.Lab can ensure better quality control while simultaneously saving both time and money. For production runs, the TopMap Metro.Lab is a perfect comparison standard for statistical process control, taking random samples at set intervals in batch processes and verifying the consistency of a manufacturing process. This allows much longer manufacturing intervals with sustained quality. Serial measurement of workpieces on pallets is also possible. Because of the TopMap's good price-performance ratio, an investment in the Metro.Lab generally pays for itself very quickly.



Fig. 4: A defective mirror holder shows a flatness measurement (>30 $\mu m)$ that fails dimensional tolerances (ISO 1101).

More Info: www.topmap.info

You will find more information on TopMap White-Light Interferometers on the internet at www.topmap.info or contact your local Polytec sales/application engineer.

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